

CCIC-SET  
Electronic Testing Building, Shahe Road, Xili, Nanshan District,  
Shenzhen, 518055, P. R. China  
TEL:86 755 26627338 Fax: 86 755 26627238

**Test Lab  
Attestation Letter**

**Date of Test:** 2015-07-15~2015-07-20

**Applicant Name:** Queclink Wireless Solutions Co.,Ltd.

**FCC ID:** YQD-GL300W

**Name of Engineer  
Performing Test:** MeiChun

**Statement of Compliance:** (Test Lab) declares that this Unit has been tested in accordance with the test method identified in this test report and that we observed it being tested. It also declares that the Unit complies with the relevant limits. All instrumentation and accessories used to test this unit for compliance to the indicated test method are calibrated regularly in accordance with ISO 17025:2005 requirements by laboratories accredited by A2LA, NVLAP, or ACLAS for the measurement parameters.

**The measurements were made at:** (Test Lab Name) CCIC Southern Electronic Product Testing (Shenzhen) Co., Ltd.  
(Address) Electronic Testing Building, Shahe Road, Xili, Nanshan District, Shenzhen, 518055, P. R. China

**Test Lab Witness-**

**Signature of Test Lab Witness:** *Shuangwen Zhang*

**Full Name, Typed:** Shuangwen Zhang

**Title of Witness:** Senior Engineer

**Email Address:** zhangsw@set.org.cn

**Phone No.:** 86-755-86131239

**Company Stamp:**



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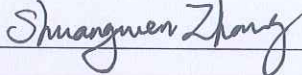
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